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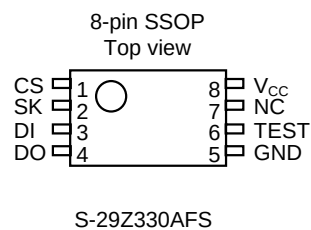
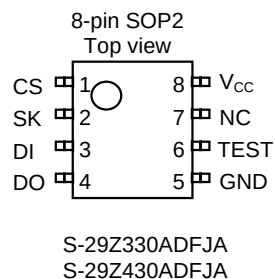
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The S-29ZX30A series are low power 4K/8K-bit E²PROM with a low operating voltage range. They are organized as 256-word × 16-bit and 512-word × 16bit, respectively. Each is capable of sequential read, at which time addresses are automatically incremented in 16-bit blocks. The instruction code is compatible with the NM93CSXX series.

■ Features

- Low power consumption
 - Standby : 2.0 μ A Max. (VCC=3.6 V)
 - Operating : 0.6 mA Max. (VCC=3.6 V)
 - : 0.4 mA Max. (VCC=2.7 V)
- Wide operating voltage range
 - Write : 0.9 to 3.6 V
 - Read : 0.9 to 3.6 V
- Sequential read capable
- Endurance : 10⁵ cycles/word
- Data retention : 10 years
- S-29Z330A : 4K bits NM93CS66 instruction code compatible
- S-29Z430A : 8K bits NM93CSXX series compatible

■ Pin Assignment



* See ■ Dimensions

Figure 1

■ Pin Functions

Table 1

Name	Pin Number		Function
	SOP2	SSOP	
CS	1	1	Chip select input
SK	2	2	Serial clock input
DI	3	3	Serial data input
DO	4	4	Serial data output
GND	5	5	Ground
TEST	6	6	Test pin (normally kept open) (can be connected to GND or Vcc)
NC	7	7	No Connection
VCC	8	8	Power supply

CMOS SERIAL E²PROM
S-29ZX30A

■ Block Diagram

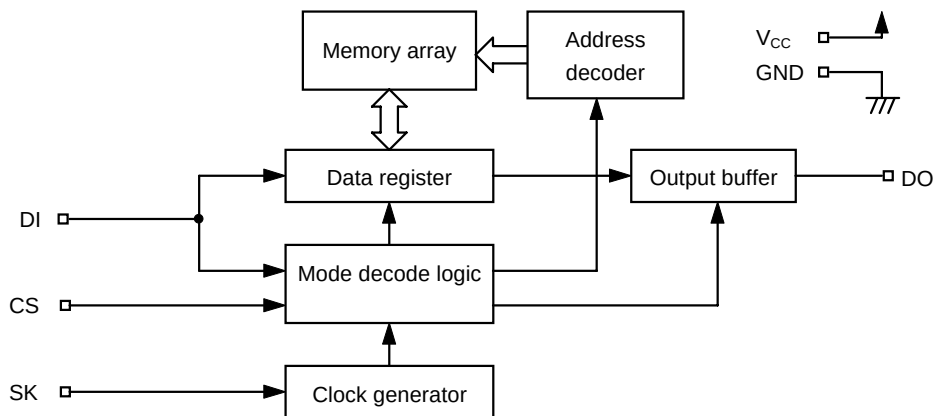


Figure 2

■ Instruction Set

Table 2

Instruction	Start Bit	Opo Code	Address		Data
			S-29Z330A	S-29Z430A	
READ (Read data)	1	10	A ₇ to A ₀	xA ₈ to A ₀	D ₁₅ to D ₀ Output*
WRITE (Write data)	1	01	A ₇ to A ₀	xA ₈ to A ₀	D ₁₅ to D ₀ Input
ERASE (Erase data)	1	11	A ₇ to A ₀	xA ₈ to A ₀	—
EWEN (Program enable)	1	00	11xxxxxx	11xxxxxxxx	—
EWDS (Program disable)	1	00	00xxxxxx	00xxxxxxxx	—

x : Doesn't matter.
* : Addresses are continuously incremented.

■ Absolute Maximum Ratings

Table 3

Parameter	Symbol	Ratings	Unit
Power supply voltage	V _{CC}	-0.3 to +7.0	V
Input voltage	V _{IN}	-0.3 to V _{CC} +0.3	V
Output voltage	V _{OUT}	-0.3 to V _{CC}	V
Storage temperature under bias	T _{bias}	-50 to +95	°C
Storage temperature	T _{stg}	-65 to +150	°C

■ **Recommended Operating Conditions**

Table 4

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Power supply voltage	V _{CC}	READ/WRITE/ERASE EWEN/EWDS	0.9	--	3.6	V
High level input voltage	V _{IH}	V _{CC} = 1.8 to 3.6 V	0.8 × V _{CC}	--	V _{CC}	V
		V _{CC} = 0.9 to 1.8 V	0.9 × V _{CC}	--	V _{CC}	V
Low level input voltage	V _{IL}	V _{CC} = 1.8 to 3.6 V	0.0	--	0.2 × V _{CC}	V
		V _{CC} = 0.9 to 1.8 V	0.0	--	0.1 × V _{CC}	V
Operating temperature	T _{op}		- 40	--	+ 85	°C

■ **Pin Capacitance**

Table 5

(T_a=25 °C, f=1.0 MHz, V_{CC}=5 V)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Input Capacitance	C _{IN}	V _{IN} =0 V	—	—	8	pF
Output Capacitance	C _{OUT}	V _{OUT} =0 V	—	—	10	pF

■ **Endurance**

Table 6

Parameter	Symbol	Min.	Typ.	Max.	Unit
Endurance	N _w	10 ⁵	—	—	cycles/word

CMOS SERIAL E²PROM

S-29ZX30A

■ DC Electrical Characteristics

Table 7

Parameter	SmbI	Conditions	V _{CC} =2.7 V to 3.6 V			V _{CC} =1.8 V to 2.7 V			V _{CC} =0.9 to 1.8 V			Unit
			Min.	Typ.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.	
Current consumption (READ)	I _{CC1}	DO unloaded	—	—	0.6	—	—	0.4	—	—	0.2	mA
Current consumption (PROGRAM)	I _{CC2}	DO unloaded	—	—	5.0	—	—	5.0	—	—	5.0	mA

Table 8

Parameter	SmbI	Conditions	V _{CC} =2.7 V to 3.6 V			V _{CC} =1.8 to 2.7 V			V _{CC} =0.9 to 1.8 V			Unit
			Min.	Typ.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.	
Standby current consumption	I _{SB}	CS=GND DO=Open Connected to V _{CC} or GND Topr=-10 ~ +70°C	—	—	1.0	—	—	1.0	—	—	1.0	μA
		CS=GND DO=Open Connected to V _{CC} or GND Topr=-40 ~ +85°C	—	—	2.0	—	—	2.0	—	—	2.0	μA
Input leakage current	I _{LI}	V _{IN} =GND to V _{CC}	—	0.1	1.0	—	0.1	1.0	—	0.1	1.0	μA
Output leakage current	I _{LO}	V _{OUT} =GND to V _{CC}	—	0.1	1.0	—	0.1	1.0	—	0.1	1.0	μA
Low level output voltage	V _{OL}	I _{OL} = 100μA	—	—	0.1	—	—	0.1	—	—	—	V
		I _{OL} = 30μA	—	—	0.1	—	—	0.1	—	—	—	V
		I _{OL} = 10μA	—	—	0.1	—	—	0.1	—	—	0.2	V
High level output voltage	V _{OH}	I _{OH} = -100μA	V _{CC} -0.7	—	—	—	—	—	—	—	—	V
		I _{OH} = -10μA	V _{CC} -0.7	—	—	V _{CC} -0.3	—	—	—	—	—	V
		I _{OH} = -5μA	V _{CC} -0.7	—	—	V _{CC} -0.3	—	—	V _{CC} -0.2	—	—	V
Write enable latch data hold voltage	V _{DH}	Only when write disable mode	0.8	—	—	0.8	—	—	0.8	—	—	V

■ AC Electrical Characteristics

Table 9

Input pulse voltage	$0.1 \times V_{CC}$ to $0.9 \times V_{CC}$
Output reference voltage	$0.5 \times V_{CC}$
Output load	100pF

Table 10

Parameter	Symble	Conditions	V _{CC} =2.7 to 3.6V			V _{CC} =1.8 to 2.7 V			V _{CC} =0.9 to 1.8V			Unit
			Min.	Typ.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.	
CS setup time	t _{CSS}		0.4	—	—	1.0	—	—	10	—	—	μs
CS hold time	t _{CSH}		0.4	—	—	1.0	—	—	10	—	—	μs
CS deselect time	t _{CDS}		0.2	—	—	0.4	—	—	4	—	—	μs
Data setup time	t _{DS}		0.4	—	—	0.8	—	—	8	—	—	μs
Data hold time	t _{DH}		0.4	—	—	0.8	—	—	8	—	—	μs
Output delay	t _{PD}	Topr=-10 to +70°C	—	—	1.0	—	—	2.0	—	—	50	μs
		Topr=-40 to +85°C	—	—	1.0	—	—	2.0	—	—	100	μs
Clock frequency	f _{SK}	Topr=-10 to +70°C	0	—	500	0	—	250	—	—	10	KHz
		Topr=-40 to +85°C	0	—	500	0	—	250	—	—	5	KHz
Clock pulse width	t _{SKH} , t _{SKL}	Topr=-10 to +70°C	1.0	—	—	2.0	—	—	50	—	—	μs
		Topr=-40 to +85°C	1.0	—	—	2.0	—	—	100	—	—	μs
Output disable time	t _{HZ1} , t _{HZ2}		0	—	0.5	0	—	1.0	0	—	50	μs
Output enable time	t _{SV}		0	—	0.5	0	—	1.0	0	—	50	μs
Programming time	t _{PR}		—	4.0	10.0	—	4.0	10.0	—	—	10.0	ms

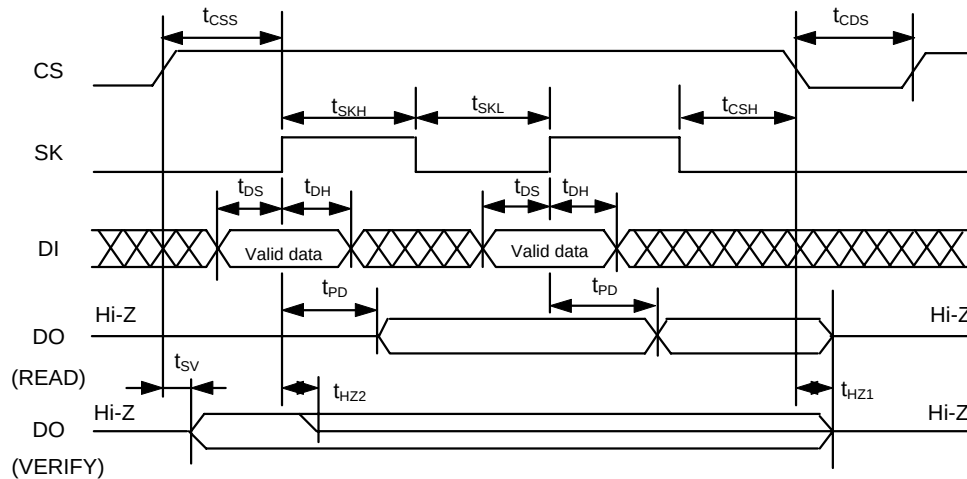


Figure 3 Read Timing

CMOS SERIAL E²PROM

S-29ZX30A

■ Operation

Instructions (in the order of start-bit, instruction, address, and data) are latched to DI in synchronization with the rising edge of SK after CS goes high. A start-bit can only be recognized when the high of DI is latched to the rising edge of SK when CS goes from low to high, it is impossible for it to be recognized as long as DI is low, even if there are SK pulses after CS goes high. Any SK pulses input while DI is low are called "dummy clocks." Dummy clocks can be used to adjust the number of clock cycles needed by the serial IC to match those sent out by the CPU. Instruction input finishes when CS goes low, where it must be between commands during t_{CDS} .

All input, including DI and SK signals, is ignored while CS is low, which is stand-by mode.

1. Read

The READ instruction reads data from a specified address. After A0 is latched at the rising edge of SK, DO output changes from a high-impedance state (Hi-Z) to low level output. Data is continuously output in synchronization with the rise of SK.

When all of the data (D15 to D0) in the specified address has been read, the data in the next address can be read with the input of another SK clock. Thus, it is possible for all of the data addresses to be read through the continuous input of SK clocks as long as CS is high.

The last address ($A_n \cdots A_1 A_0 = 1 \cdots 11$) rolls over to the top address ($A_n \cdots A_1 A_0 = 0 \cdots 00$).

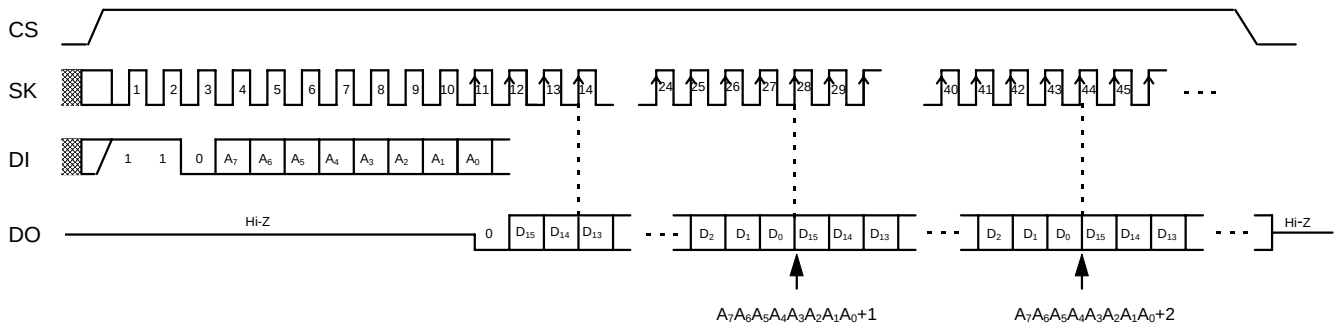


Figure 4 Read Timing (S-29Z330A)

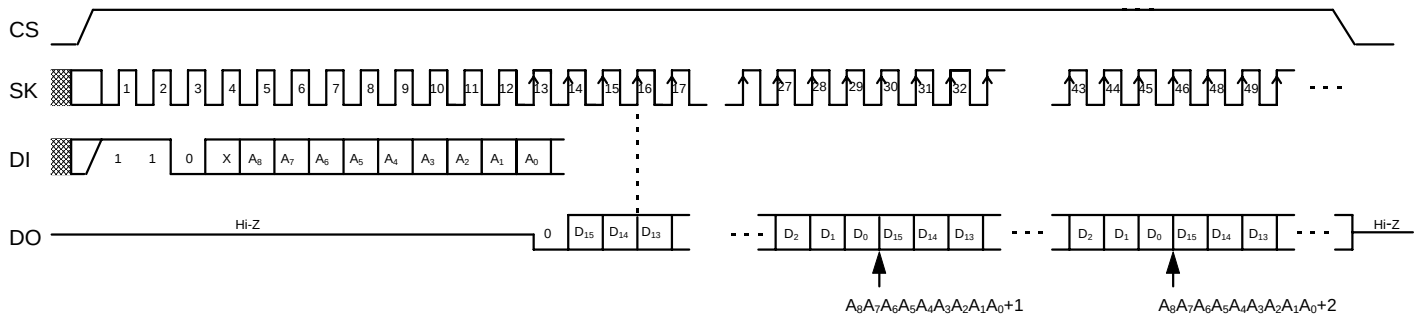


Figure 5 Read Timing (S-29Z430A)

2. Write (WRITE, ERASE)

There are two write instructions, WRITE and ERASE. Each automatically begins writing to the non-volatile memory when CS goes low at the completion of the specified clock input.

The write operation is completed in 10 ms (t_{PR} Max.), and the typical write period is less than 4 ms. In the S-29ZX30A series, it is easy to VERIFY the completion of the write operation in order to minimize the write cycle by setting CS to high and checking the DO pin, which is low during the write operation and high after its completion. This VERIFY procedure can be executed over and over again. There are two methods to detect a change in the DO output. One is to detect a change from low to high setting CS to high, and the other is to detect a change from low to high as a result of repetitious operations of returning the CS to low after setting CS to high and checking the DO output.

Because all SK and DI inputs are ignored during the write operation, any input of instruction will also be disregarded. When DO outputs high after completion of the write operation or if it is in the high-impedence state (Hi-Z), the input of instructions is available. Even if the DO pin remains high, it will enter the high-impedence state upon the recognition of a high of DI (start-bit) attached to the rising edge of an SK pulse. (see Figure 3).

DI input should be low during the VERIFY procedure.

2.1 WRITE

This instruction writes 16-bit data to a specified address.

After changing CS to high, input a start-bit, op-code (WRITE), address, and 16-bit data. If there is a data overflow of more than 16 bits, only the last 16-bits of the data is considered valid. Changing CS to low will start the WRITE operation. It is not necessary to make the data "1" before initiating the WRITE operation.

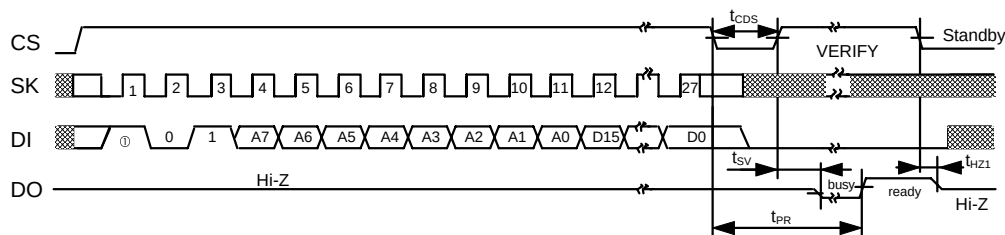


Figure 6 WRITE Timing (S-29Z330A)

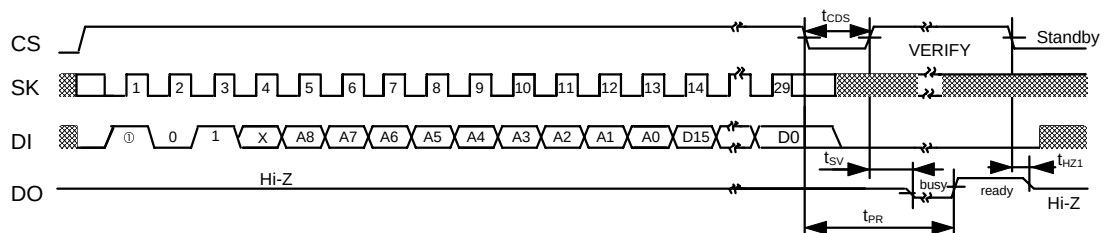


Figure 7 WRITE Timing (S-29Z430A)

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2.2 ERASE

This command erases 16-bit data in a specified address. After changing CS to high, input a start-bit, op-code (ERASE), and address. It is not necessary to input data. Changing CS to low will start the ERASE operation, which changes every bit of the 16 bit data to "1."

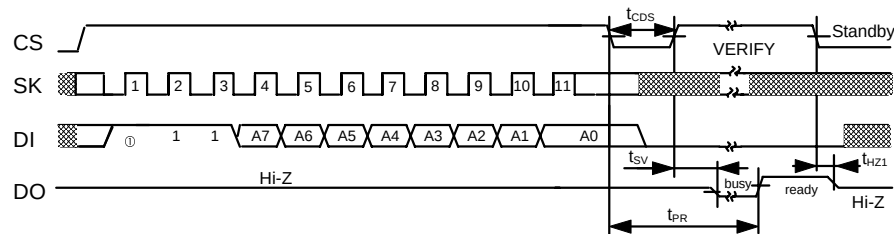


Figure 8 ERASE Timing (S-29Z330A)

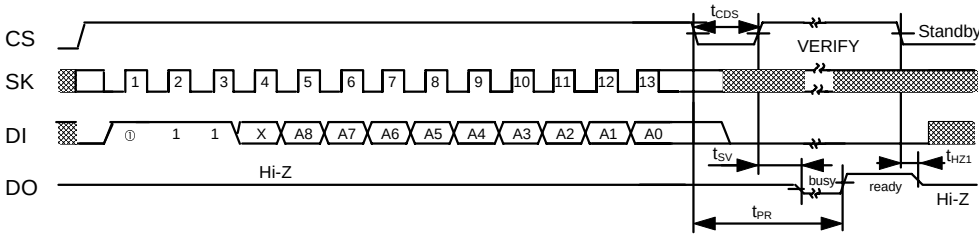


Figure 9 ERASE Timing (S-29Z430A)

3. Write enable (EWEN) and Write disable (EWDS)

The EWEN instruction puts the S-29ZX30A series into write enable mode, which accepts WRITE and ERASE instructions. The EWDS instruction puts the S-29ZX30A series into write disable mode, which refuses WRITE and ERASE instructions. The S-29ZX30A series powers on in write disable mode, which protects data against unexpected, erroneous write operations caused by noise and/or CPU malfunctions. It should be kept in write disable mode except when performing write operations.

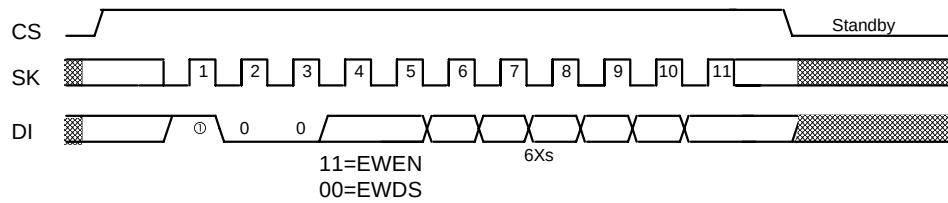


Figure 10 EWEN/EWDS Timing (S-29Z330A)

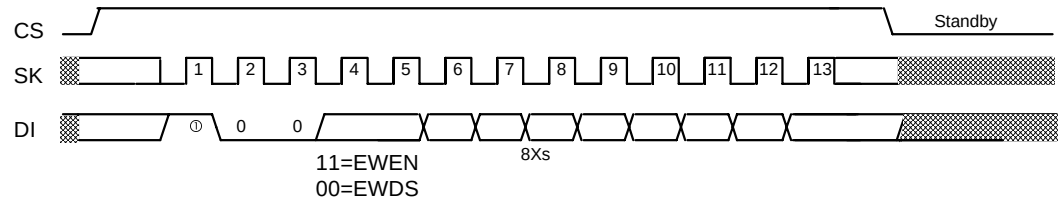


Figure 11 EWEN/EWDS Timing (S-29Z430A)

■ Receiving a Start-Bit

A start bit can be recognized by latching the high level of DI at the rising edge of SK after changing CS to high (Start-bit Recognition). The write operation begins by inputting the write instruction and setting CS to low. The DO pin then outputs low during the write operation and high at its completion by setting CS to high (Verify Operation). Therefore, only after a write operation, in order to accept the next command by having CS go high, will the DO pin switch from a state of high-impedence to a state of data output; but if it recognizes a start-bit, the DO pin returns to a state of high-impedence (see Figure 3).

■ Three-wire Interface (DI-DO direct connection)

Although the normal configuration of a serial interface is a 4-wire interface to CS, SK, DI, and DO, a 3-wire interface is also a possibility by connecting DI and DO. However, since there is a possibility that the DO output from the serial memory IC will interfere with the data output from the CPU with a 3-wire interface, install a resistor between DI and DO in order to give preference to data output from the CPU to DI (See Figure 12).

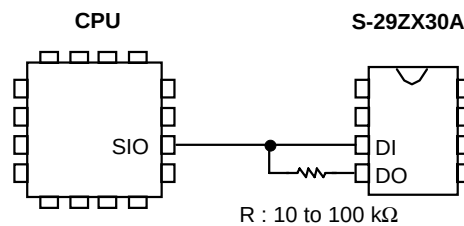


Figure 12

CMOS SERIAL E²PROM

S-29ZX30A

■ Dimensions (Unit : mm)

2. 8-pin SOP (S-29ZX30ADFJA)

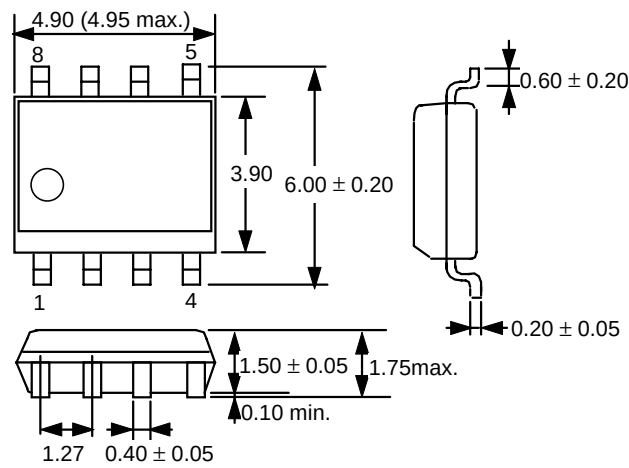


Figure 13

Markings (S-29ZX30ADFJA)

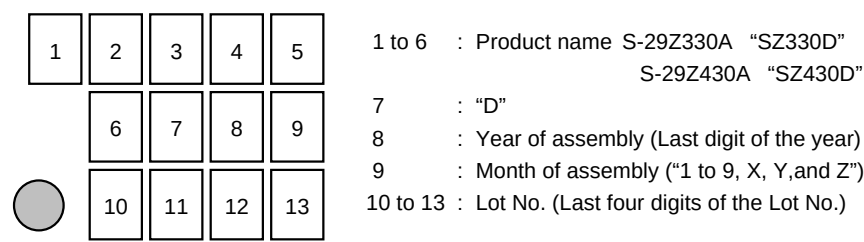


Figure 14

3. 8-pin SSOP (S-29Z330AFS)

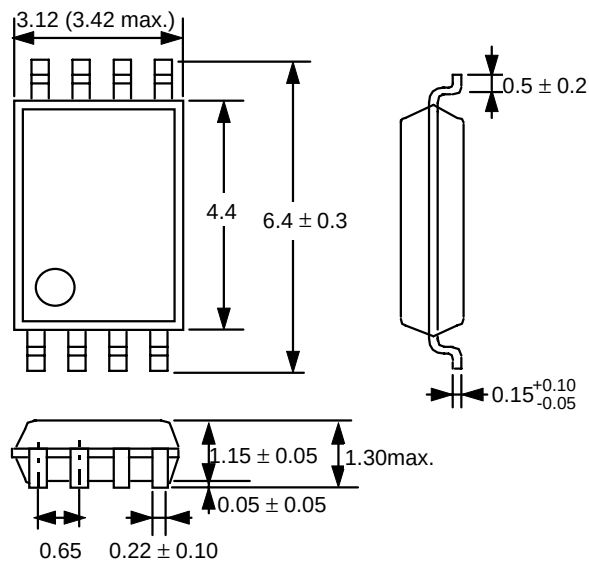


Figure 15

Markings (S-29Z330AFS)

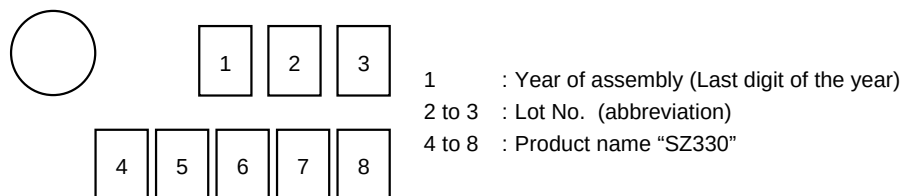
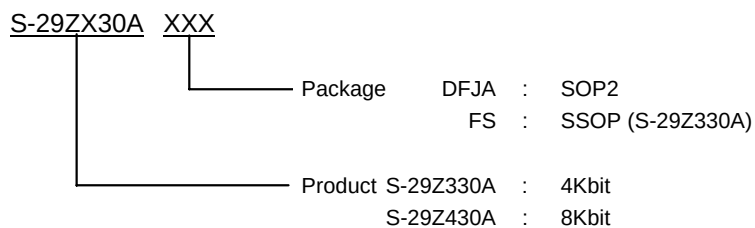


Figure 16

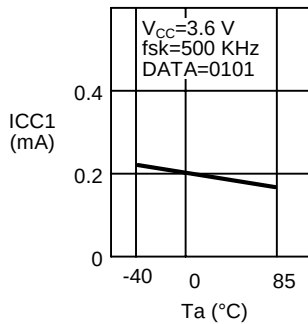
■ Ordering Information



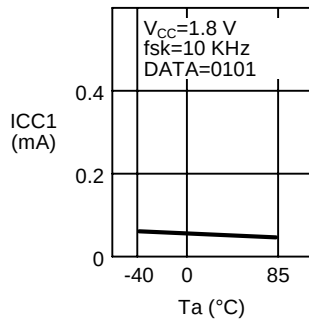
■ Characteristics

1. DC Characteristics

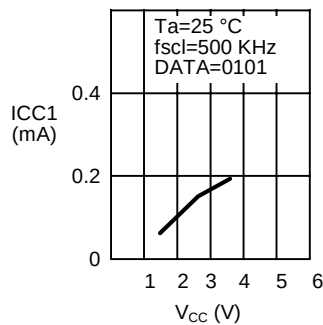
1.1 Current consumption (READ) I_{CC1} --
Ambient temperature T_a



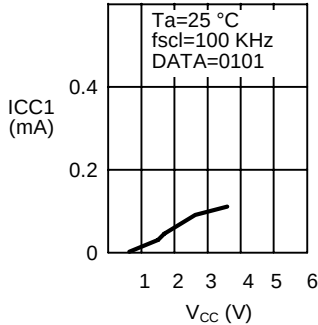
1.2 Current consumption (READ) I_{CC1} --
Ambient temperature T_a



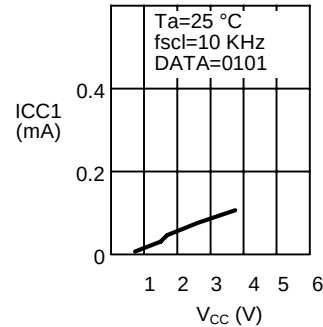
1.3 Current consumption (READ) I_{CC1} --
Power supply voltage V_{CC}



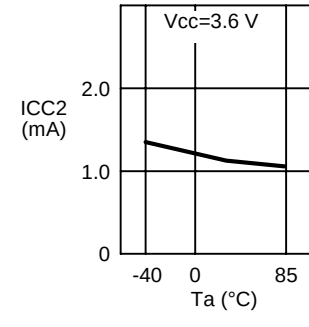
1.4 Current consumption (READ) I_{CC1} --
Power supply voltage V_{CC}



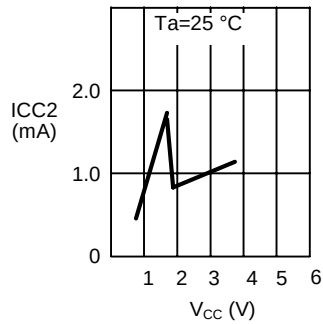
1.5 Current consumption (READ) I_{CC1} --
Power supply voltage V_{CC}



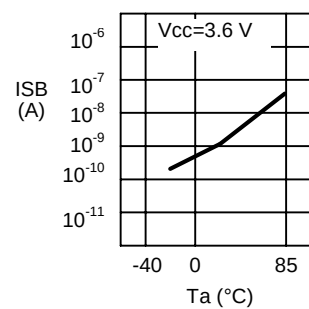
1.6 Current consumption (WRITE) I_{CC2} --
Ambient temperature T_a



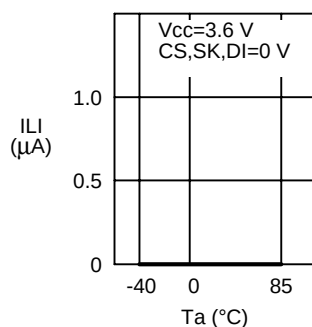
1.7 Current consumption (WRITE) I_{CC2} --
Power supply voltage V_{CC}



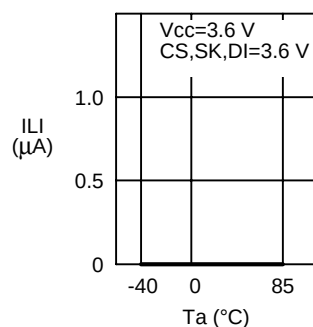
1.8 Standby current consumption I_{SB} --
Ambient temperature T_a



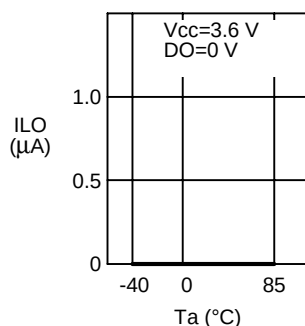
1.9 Input leakage current I_{LI} --
Ambient temperature T_a



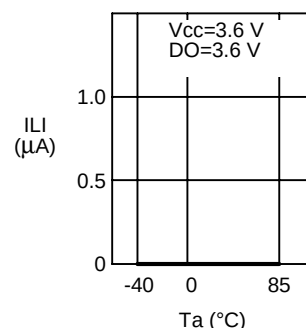
1.10 Input leakage current I_{LI} --
Ambient temperature T_a



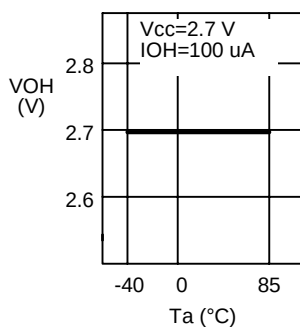
1.11 Output leakage current I_{LO} --
Ambient temperature T_a



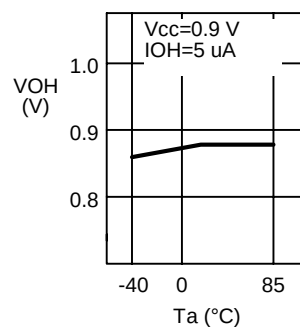
1.12 Output leakage current I_{LO} --
Ambient temperature T_a



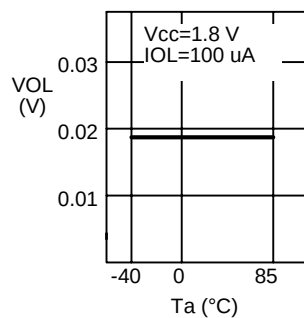
1.13 High level output voltage V_{OH} --
Ambient temperature T_a



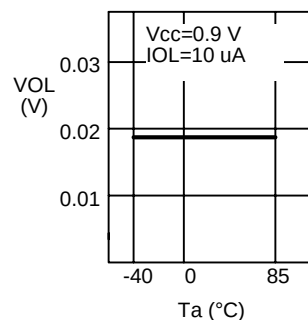
1.14 High level output voltage V_{OH} --
Ambient temperature T_a



1.15 Low level output voltage V_{OL} --
Ambient temperature T_a



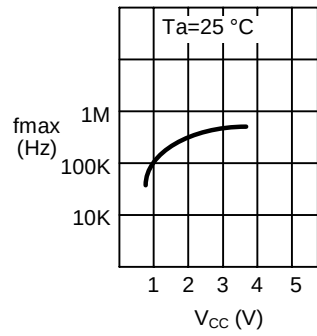
1.16 Low level output voltage V_{OL} --
Ambient temperature T_a



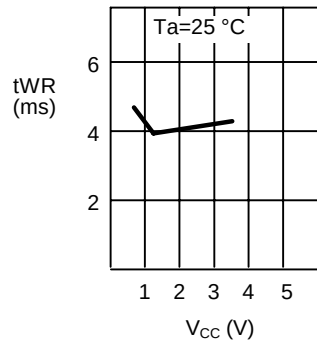
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2. AC Characteristics

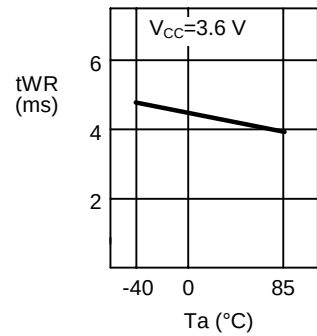
2.1 Maximum operating frequency f_{max} --
Power supply voltage V_{CC}



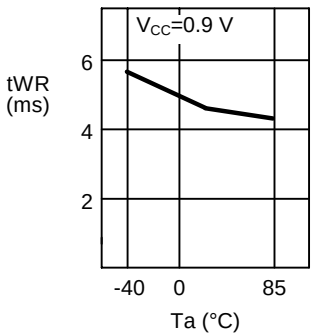
2.2 Program time t_{PR} --
Power supply voltage V_{CC}



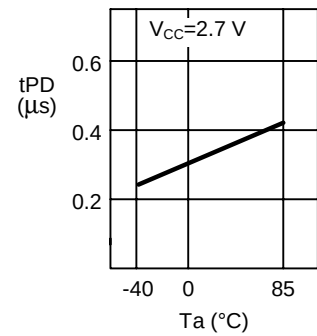
2.3 Program time t_{PR} --
Ambient temperature T_a



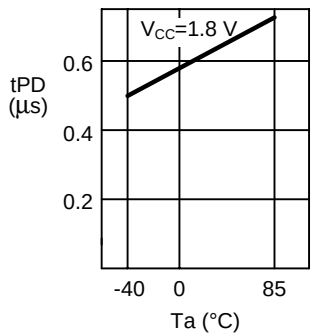
2.4 Program time t_{PR} --
Ambient temperature T_a



2.5 Data output delay time t_{PD} --
Ambient temperature T_a



2.6 Data output delay time t_{PD} --
Ambient temperature T_a



2.7 Data output delay time t_{PD} --
Ambient temperature T_a

